Se	arch	Notes	;

,	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/070,617	SAKUMA, EMIKO	
	Examiner	Art Unit	
	Jacob Meek	2637	

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Class	Subclass	Date	Examiner
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Class	Subclass	Date	Examiner

SEARCH NO (INCLUDING SEARCH	STRATEGY)
	DATE	EXMR
East: see search history	1/20/2006	JM
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